MMBT4403WT1

Switching Transistor

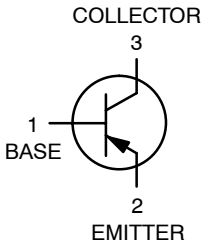
PNP Silicon

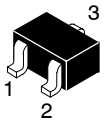
ON Semiconductor®

http://onsemi.com

Features

- Moisture Sensitivity Level: 1
- ESD Rating: Human Body Model; 4 kV,
  Machine Model; 400 V
- Pb−Free Package is Available





SC−70
CASE 419
STYLE 3

MAXIMUM RATINGS

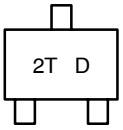
Rating	Symbol	Value	Unit
Collector−Emitter Voltage	V_{CEO}	−40	Vdc
Collector−Base Voltage	V_{CBO}	−40	Vdc
Emitter−Base Voltage	V_{EBO}	−5.0	Vdc
Collector Current − Continuous	I_C	−600	mAdc

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Total Device Dissipation FR−5 Board T_A = 25°C	P_D	150	mW
Thermal Resistance, Junction−to−Ambient	$R_{\theta JA}$	833	°C/W
Junction and Storage Temperature	T_J, T_{stg}	−55 to +150	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

MARKING DIAGRAM



2T = Specific Device Code
D = Date Code

ORDERING INFORMATION

Device	Package	Shipping†
MMBT4403WT1	SC−70	3000/Tape & Reel
MMBT4403WT1G	SC−70 (Pb−Free)	3000/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Collector−Emitter Breakdown Voltage (Note 1) (I_C = −1.0 mAdc, I_B = 0)	$V_{(BR)CEO}$	−40	−	Vdc
Collector−Base Breakdown Voltage (I_C = −0.1 mAdc, I_E = 0)	$V_{(BR)CBO}$	−40	−	Vdc
Emitter−Base Breakdown Voltage (I_E = −0.1 mAdc, I_C = 0)	$V_{(BR)EBO}$	−5.0	−	Vdc
Base Cutoff Current (V_{CE} = −35 Vdc, V_{EB} = −0.4 Vdc)	I_{BEV}	−	−0.1	μAdc
Collector Cutoff Current (V_{CE} = −35 Vdc, V_{EB} = −0.4 Vdc)	I_{CEX}	−	−0.1	μAdc
ON CHARACTERISTICS				
DC Current Gain (I_C = −0.1 mAdc, V_{CE} = −1.0 Vdc) (I_C = −1.0 mAdc, V_{CE} = −1.0 Vdc) (I_C = −10 mAdc, V_{CE} = −1.0 Vdc) (I_C = −150 mAdc, V_{CE} = −2.0 Vdc) (Note 1) (I_C = −500 mAdc, V_{CE} = −2.0 Vdc) (Note 1)	h_{FE}	 30 60 100 100 20	 − − − 300 −	−
Collector−Emitter Saturation Voltage (Note 1) (I_C = −150 mAdc, I_B = −15 mAdc) (I_C = −500 mAdc, I_B = −50 mAdc)	$V_{CE(sat)}$	 − −	 −0.4 −0.75	Vdc
Base−Emitter Saturation Voltage (Note 1) (I_C = −150 mAdc, I_B = −15 mAdc) (I_C = −500 mAdc, I_B = −50 mAdc)	$V_{BE(sat)}$	 −0.75 −	 −0.95 −1.3	Vdc
SMALL−SIGNAL CHARACTERISTICS				
Current−Gain − Bandwidth Product (I_C = −20 mAdc, V_{CE} = −10 Vdc, f = 100 MHz)	f_T	200	−	MHz
Collector−Base Capacitance (V_{CB} = −10 Vdc, I_E = 0, f = 1.0 MHz)	C_{cb}	−	8.5	pF
Emitter−Base Capacitance (V_{BE} = −0.5 Vdc, I_C = 0, f = 1.0 MHz)	C_{eb}	−	30	pF
Input Impedance (I_C = −1.0 mAdc, V_{CE} = −10 Vdc, f = 1.0 kHz)	h_{ie}	1.5	15	kΩ
Voltage Feedback Ratio (I_C = −1.0 mAdc, V_{CE} = −10 Vdc, f = 1.0 kHz)	h_{re}	0.1	8.0	X 10^{-4}
Small−Signal Current Gain (I_C = −1.0 mAdc, V_{CE} = −10 Vdc, f = 1.0 kHz)	h_{fe}	60	500	−
Output Admittance (I_C = −1.0 mAdc, V_{CE} = −10 Vdc, f = 1.0 kHz)	h_{oe}	1.0	100	μmhos
SWITCHING CHARACTERISTICS				
Delay Time	(V_{CC} = −30 Vdc, V_{EB} = −2.0 Vdc, I_C = −150 mAdc, I_{B1} = −15 mAdc)	t_d	−	15	ns
Rise Time		t_r	−	20	
Storage Time	(V_{CC} = −30 Vdc, I_C = −150 mAdc, I_{B1} = I_{B2} = −15 mAdc)	t_s	−	225	ns
Fall Time		t_f	−	30	

1. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%.

SWITCHING TIME EQUIVALENT TEST CIRCUIT

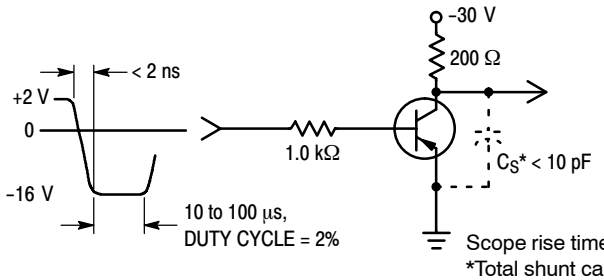


Figure 1. Turn−On Time

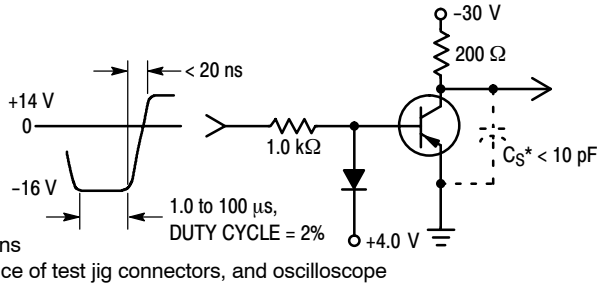


Figure 2. Turn−Off Time

Scope rise time < 4.0 ns
*Total shunt capacitance of test jig connectors, and oscilloscope

TRANSIENT CHARACTERISTICS

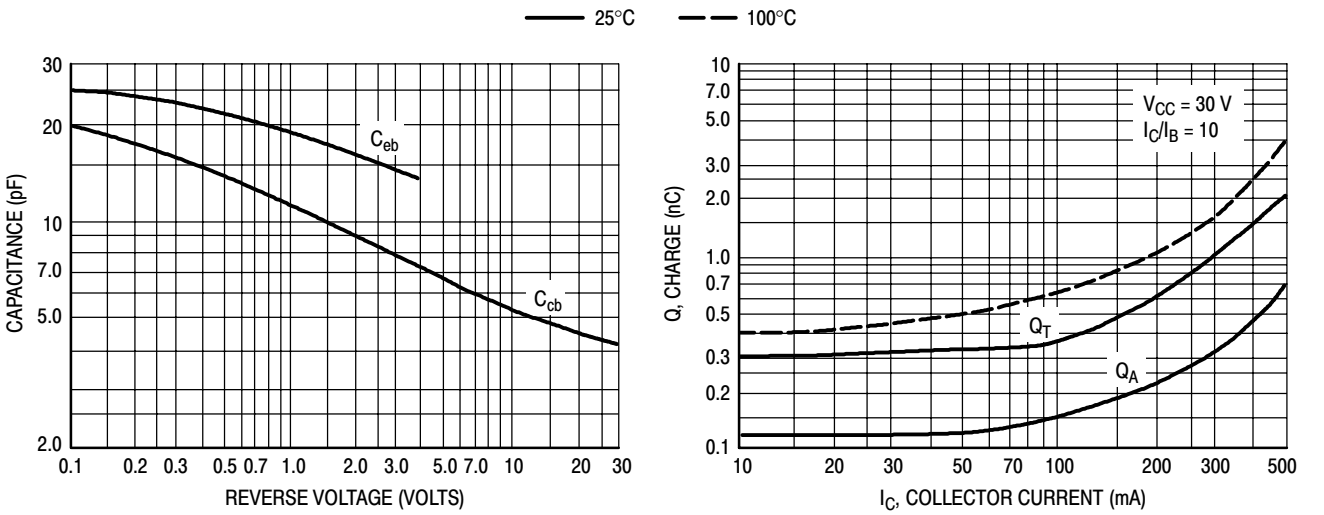


Figure 3. Capacitances

Figure 4. Charge Data

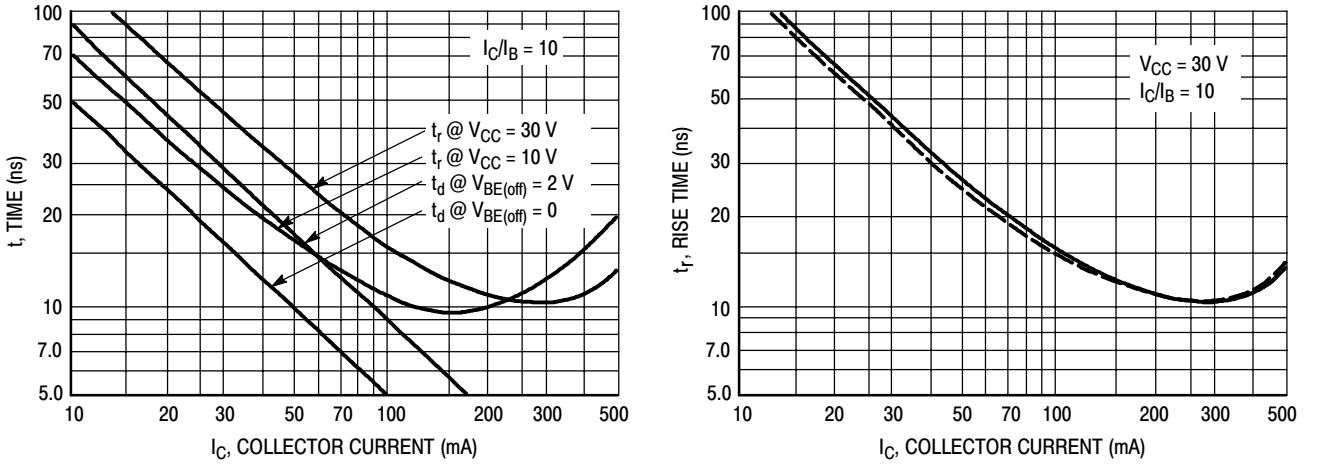


Figure 5. Turn−On Time

Figure 6. Rise Time

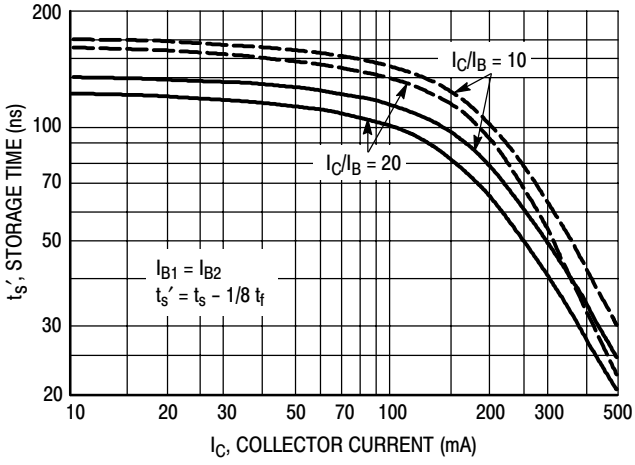


Figure 7. Storage Time

SMALL−SIGNAL CHARACTERISTICS NOISE FIGURE

V_{CE} = −10 Vdc, T_A = 25°C; Bandwidth = 1.0 Hz

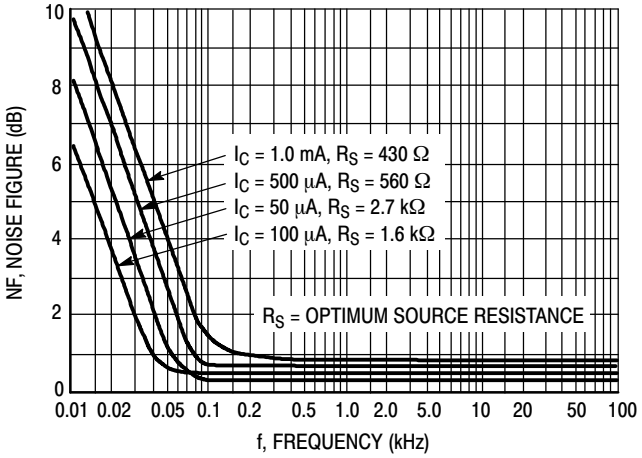


Figure 8. Frequency Effects

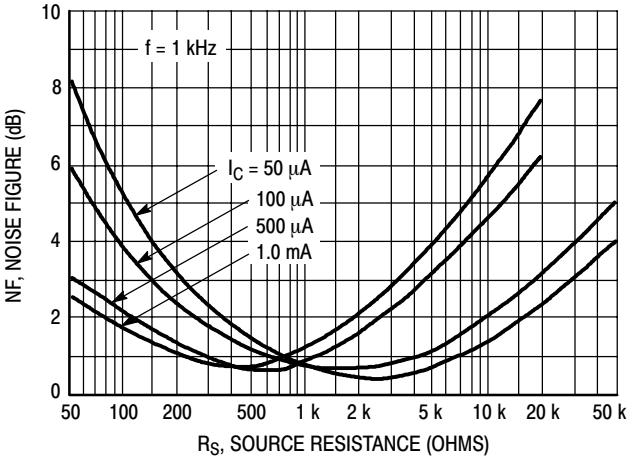


Figure 9. Source Resistance Effects

h PARAMETERS

V_{CE} = 10 Vdc, f = 1.0 kHz, T_A = 25°C

This group of graphs illustrates the relationship between h_{fe} and other "h" parameters for this series of transistors. To obtain these curves, a high−gain and a low−gain unit were selected from the MMBT4403LT1 lines, and the same units were used to develop the correspondingly numbered curves on each graph.

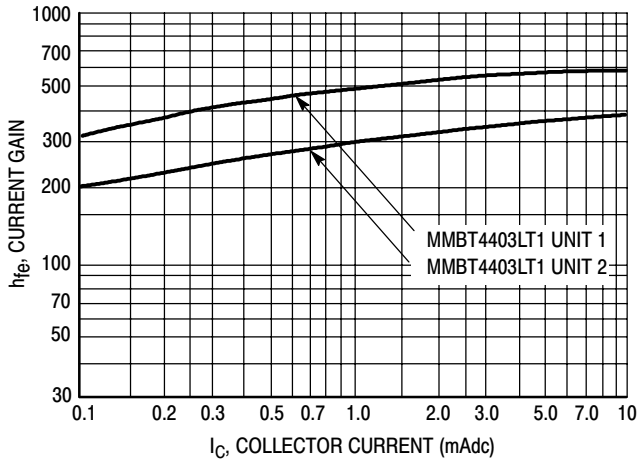


Figure 10. Current Gain

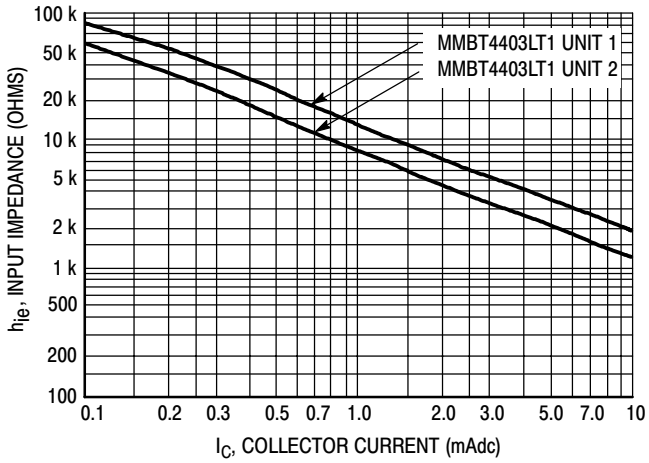


Figure 11. Input Impedance

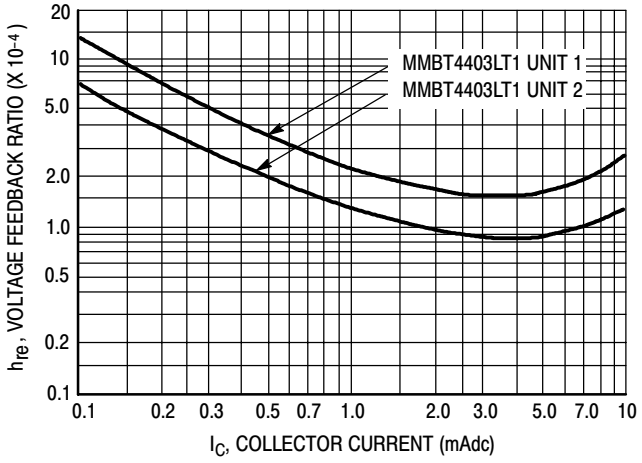


Figure 12. Voltage Feedback Ratio

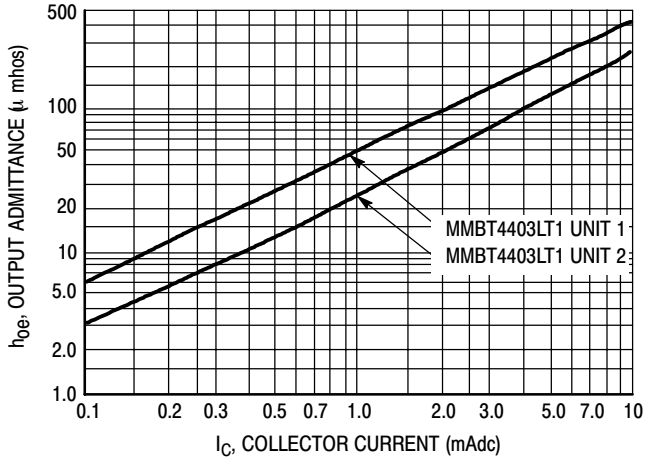


Figure 13. Output Admittance

STATIC CHARACTERISTICS

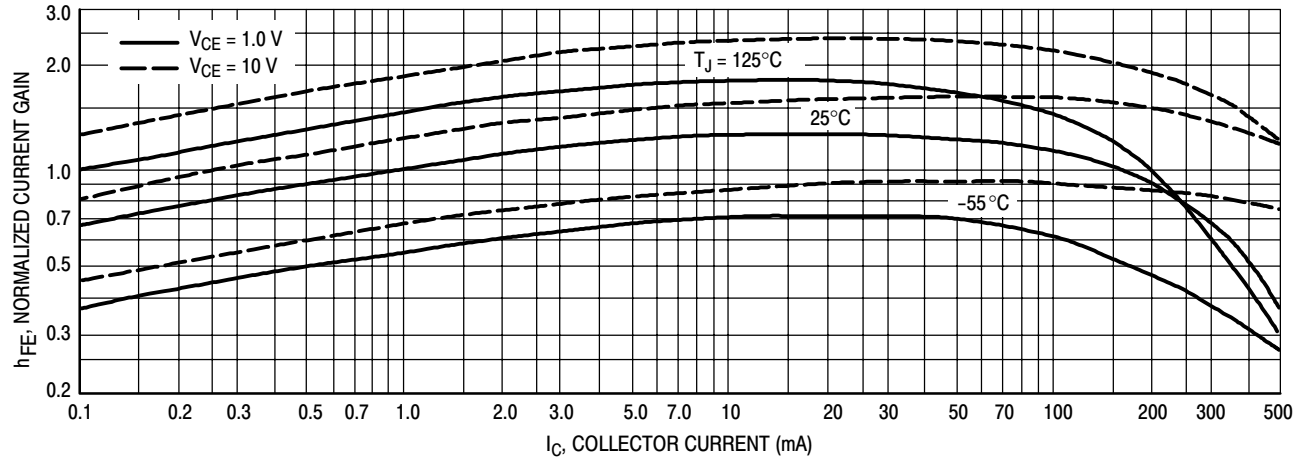


Figure 14. DC Current Gain

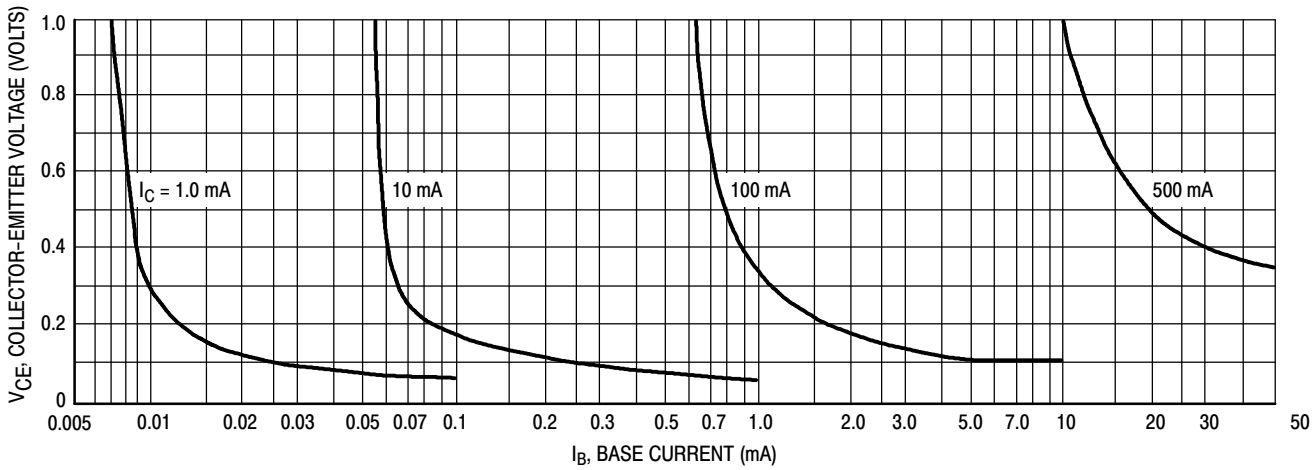


Figure 15. Collector Saturation Region

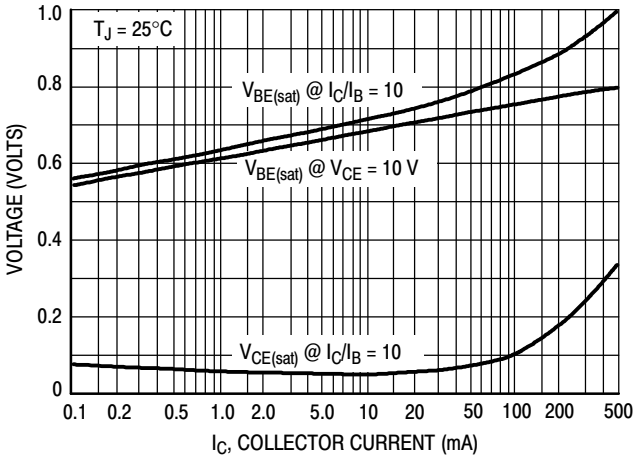


Figure 16. "On" Voltages

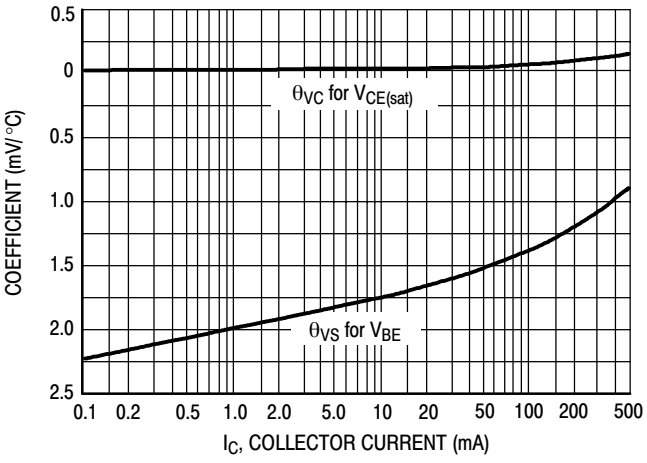
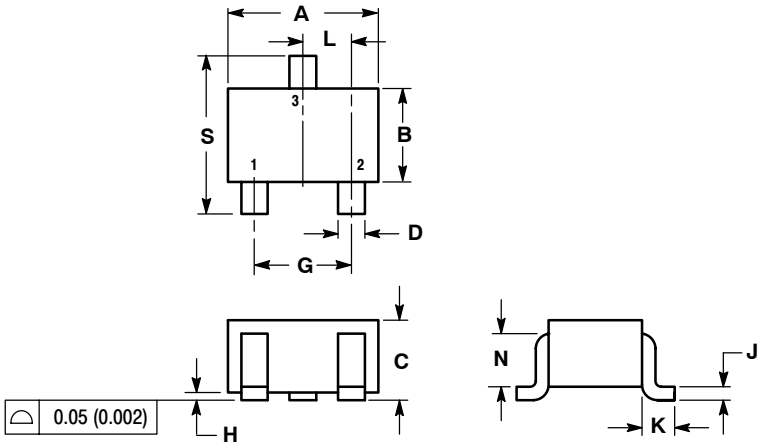


Figure 17. Temperature Coefficients

PACKAGE DIMENSIONS

SC−70/SOT−323
CASE 419−04
ISSUE L

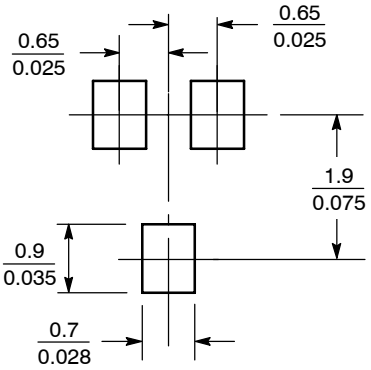


NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
A	0.071	0.087	1.80	2.20
B	0.045	0.053	1.15	1.35
C	0.032	0.040	0.80	1.00
D	0.012	0.016	0.30	0.40
G	0.047	0.055	1.20	1.40
H	0.000	0.004	0.00	0.10
J	0.004	0.010	0.10	0.25
K	0.017 REF		0.425 REF	
L	0.026 BSC		0.650 BSC	
N	0.028 REF		0.700 REF	
S	0.079	0.095	2.00	2.40

STYLE 3:
PIN 1. BASE
2. EMITTER
3. COLLECTOR

SOLDERING FOOTPRINT*



SCALE 10:1 $\left(\frac{\text{mm}}{\text{inches}}\right)$

SC−70/SOT−323

*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:
Literature Distribution Center for ON Semiconductor
P.O. Box 61312, Phoenix, Arizona 85082−1312 USA
Phone: 480−829−7710 or 800−344−3860 Toll Free USA/Canada
Fax: 480−829−7709 or 800−344−3867 Toll Free USA/Canada
Email: orderlit@onsemi.com

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Japan: ON Semiconductor, Japan Customer Focus Center
2−9−1 Kamimeguro, Meguro−ku, Tokyo, Japan 153−0051
Phone: 81−3−5773−3850

ON Semiconductor Website: http://onsemi.com

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